

## Model **AE-361A** High Cost Performance, 1kHz/120Hz MLCC Capacitor Checker.

Most suitable model for inspection on taping machine of MLCC Capacitor

### Characteristic

- Ultra high speed(Measurement time): 1msec.[1kHz]、8.34msec.[120Hz]
- It is poor contact detection of the probe at the time of 2 terminal measurement by measurement abnormality detection.
- Available to make the contact check to watch the contact condition of probe contact.
- Measurement frequency: 1kHz/120Hz $\pm$ 0.1%(a sine wave)
- Change possibility of series equivalent circuit/parallel equivalent circuit.
- Available to measure by constant voltage for the capacitor with the voltage dependence.  
( It is not supported some range )
- 4 $\frac{1}{2}$ figures(15000) display and available HI/GO/LO judgment by comparator
- BIN function[Option]: It is available to classified to 14 ranks maximum and out of BIN the C measurement values.
- “RS-232C” and “printer output” function (Centronics conformity) are as normal.  
( “GP-IB” is option)
- Supplies a measurement electric current by intermittent in order to reduce the abrasion of the probe contact.



**AEMIC CORPORATION,**

Model **AE-361A** High Cost Performance, 1kHz/120Hz MLCC Capacitor Checker.**SPECIFICATIONS** **TENTATIVE**

Measuring range and Accuracy (DF&lt;0.1 Ambient temperature 23°C±5°C)

Range	Measuring Range	Resolution	Accuracy [In case of FAST, Accuracy of C and DF becomes double]		Measuring Voltage[rms]
			1kHz	120Hz	
15pF	0.000pF~15.000pF	0.001pF	C: Within±0.25% of rdg±25dg	----	1V±5%
		DF: 0.0001	DF: Within±0.003±0.00025×(Cr/Cx)	----	0.5V±5%
150pF	0.00pF~150.00pF	0.01pF	C: Within±0.15% of rdg±10dg	----	1V±5%
		DF: 0.0001	DF: Within±0.002±0.0001×(Cr/Cx)	----	0.5V±5%
1.5nF	0.0pF~1500.0pF	0.1pF	C: Within±0.15% of rdg±10dg	----	1V±5%
		DF: 0.0001	DF: Within±0.002±0.0001×(Cr/Cx)	----	0.5V±5%
15nF	0.000nF~15.000nF	0.001nF	C: Within±0.15% of rdg±10dg	----	1V±5%
		DF: 0.0001	DF: Within±0.002±0.0001×(Cr/Cx)	----	0.5V±5%
150nF	0.00nF~150.00nF	0.01nF	C: Within±0.15% of rdg±10dg	----	1V±5%
		DF: 0.0001	DF: Within±0.002±0.0001×(Cr/Cx)	----	0.5V±5%
1.5μF	0.0nF~1500.0nF	0.1nF	C: Within±0.15% of rdg±10dg	C: Within±0.15% of rdg±10dg	1V±5%
		DF: 0.0001	DF: Within±0.002±0.0001×(Cr/Cx)	DF: Within±0.002±0.0001×(Cr/Cx)	0.5V±5%
15μF	0.000μF~15.000μF	0.001μF	C: Within±0.3% of rdg±20dg	C: Within±0.15% of rdg±10dg	1V±5%
		DF: 0.0001	DF: Within±0.003±0.0002×(Cr/Cx)	DF: Within±0.002±0.0002×(Cr/Cx)	0.5V±5%
150μF	0.00μF~150.00μF	0.01μF	C: Within±1% of rdg±50dg	C: Within±0.5% of rdg±25dg	1kHz : 1V/0.5V +5%~-20%
		DF: 0.0001	DF: Within±0.005±0.0005×(Cr/Cx)	DF: Within±0.003±0.0005×(Cr/Cx)	120Hz : 0.5V±5%
1.5mF	0.0μF~1500.0μF	0.1μF	----	C: Within±1.5% of rdg±50dg	120Hz/0.5V+5%~-25%
		DF: 0.0001	----	DF: Within±0.01±0.001×(Cr/Cx)	

※In case of Measuring Voltage is 0.5Vrms, Accuracy of C and DF becomes double.

Measurement Method	3 or 5 terminal measurement [Available to select the measuring method on each range]
Measuring Frequency	1kHz/120Hz±0.1%, sine wave
Output Impedance	Approx. 2Ω
Straycapacity revision range	Approx. 20pF
temperature coefficient	Within ±100ppm/°C [f.s and zero]
Measurement time	【Free running】FAST: Approx.1~5 time/sec. SLOW: FAST×N(N: The setting number of "average") 【Start trigger signal】FAST: 1msec.[1kHz], 8.34msec.[120Hz]
Measuring range	Capacitance : 0~15000 DF : 0.000~0.500
Use environment	Temperature: 0°C~+50°C, Humidity: Less than 85%
Power supply	AC85V~265V, 50~60Hz, Approx. 50VA
Outer dimension	250(W)×99(H)×300(D)mm
Weight	Approx. 3.5kg

## Option

GP-IB	
BIN function	C: 14 ranks & out of bin.

※ We will change the specifications of the catalogue without notice by improvement.

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